MT3264S

N-Channel Power®MOSFET

40V;80A;5.5mΩ

General Description

This N-channel MOSFET is produced using MOS-TECH Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

Features

- $R_{DS(on)} = 5.5 m\Omega (Typ.) @ V_{GS} = 10 V, I_D = 15 A$
- High performance trench technology for extremely low RDS(ON)
- · High power and current handling capability
- RoHS compliant

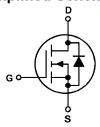
Applications

DC/DC converters



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Simplified Schematic



MARKING DIAGRAM & PIN ASSIGNMENT



Absolute Maximum Ratings(T_A = 25°C unless otherwise noted)

Symbol		Parameter		Ratings	Units
V _{DSS}	Drain to Source Voltage			40	V
V_{GSS}	Gate to Source Voltage			±20	V
I _D	Drain Current	-Continuous (T _C = 25°C)	(Note 1)	80	Α
I _{DM}	Drain Current	- Pulsed		195	Α
E _{AS}	Single Pulsed Avalanche Energy		(Note 2)	365	mJ
Ь	Power Dissipation	(T _C = 25°C)		50	W
P _D	Fower Dissipation	- Derate above 25°C		1.0	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	οС	

Thermal Characteristics

Symbol	Parameter	Ratings	Units	
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.75	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	40	· C/VV	

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Package Marking ar	nd Ordering	Information T _C :	= 25°C unless otherwise noted
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Device Marking	Device	Package	Reel Size	Tape Width	Quantity
MT3264S	MT3264S	TO-252-2L	-	-	2500 units

Electrical Characteristics

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units			
Off Characteristics									
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_J = 25^{\circ} C$	40	-	-	V			
I	Zero Gate Voltage Drain Current	$V_{DS} = 32V, V_{GS} = 0V$	-	-	1	uА			
DSS Zero Gate Voltage Drain Current	Zero Gate Voltage Brain Guirent	$V_{DS} = 32V, T_{C} = 150^{\circ}C$	-	-	30	μΑ			
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	±100	nA			

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	VGS = VDS, ID = 250μA	1	1.7	3	V
		V _{GS} = 10V, I _D = 15 A	-	5.5	6.5	
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 15 A$ $T_J = 175$ °C	-	12	-	mΩ

Dynamic Characteristics

C _{iss}	Input Capacitance	\/ - OF\/ \/ - O\	,	-	2500	3350	pF
C _{oss}	Output Capacitance	$V_{DS} = 25V, V_{GS} = 0V$	$V_{DS} = 25V, V_{GS} = 0V$ f = 1MHz		420	580	рF
C _{rss}	Reverse Transfer Capacitance	1 - 1101112			220	340	pF
R _G	Gate Resistance	$V_{GS} = 0V, f = 1MHz$		-	1.5	-	Ω
Q _{g(tot)}	Total Gate Charge at 10V	V _{GS} = 0V to 10V		-	93	120	nC
Q _{g(th)}	Threshold Gate Charge	V _{GS} = 0V to 2V	V _{DS} = 44V	-	25.5	33	nC
Q_{gs}	Gate to Source Gate Charge		I _D = 15A	-	35	-	nC
Q _{gs2}	Gate Charge Threshold to Plateau		I _g = 1mA		9.5	-	nC
Q _{gd}	Gate to Drain "Miller" Charge			-	32	-	nC

Switching Characteristics

t _{ON}	Turn-On Time		-	97	110	ns
t _{d(on)}	Turn-On Delay Time	V_{DD} = 28V, I_{D} = 15 A V_{GS} = 10V, R_{GEN} = 2.5 Ω	-	13	25	ns
t _r	Turn-On Rise Time		-	107	205	ns
t _{d(off)}	Turn-Off Delay Time		-	42	60	ns
t _f	Turn-Off Fall Time		-	18	46	ns
t _{OFF}	Turn-Off Time		-	60	83	ns

Drain-Source Diode Characteristics

V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0V, I _{SD} = 15 A	-	0.85	1.3	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0V, I _{SD} = 15A	-	43.3	-	ns
Q _{rr}	Reverse Recovery Charge	dI _F /dt = 100A/μs	-	70.8	-	nC

Notes: 1: Calculated continuous current based on maximum allowable junction temperature. Package limited to 75A continuous, see Figure 9. 2: L = 0.21mH, I_{AS} = 59A, V_{DD} = 50V, V_{GS} = 10V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C

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Typical Performance Characteristics

Figure 1. On-Region Characteristics

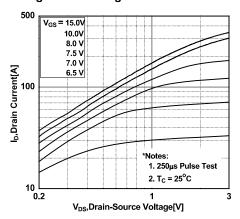


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

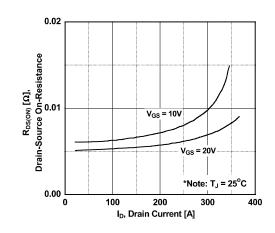


Figure 5. Capacitance Characteristics

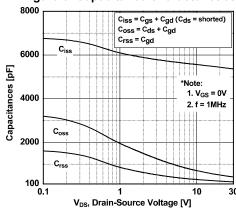


Figure 2. Transfer Characteristics

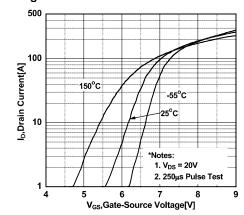


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

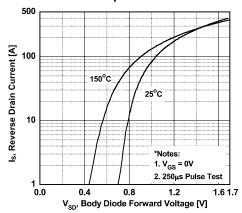
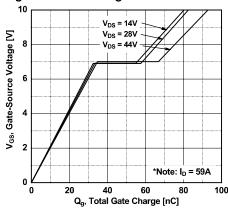


Figure 6. Gate Charge Characteristics



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Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

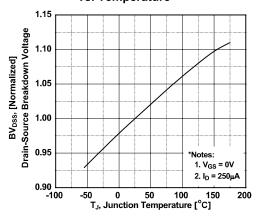


Figure 9. Maximum Safe Operating Area

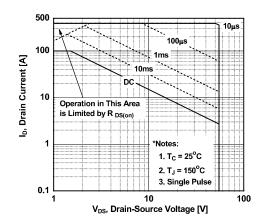


Figure 8. On-Resistance Variation vs. Temperature

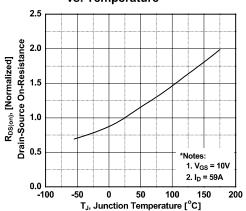


Figure 10. Maximum Drain Current vs. Case Temperature

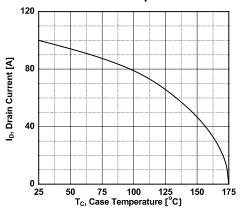
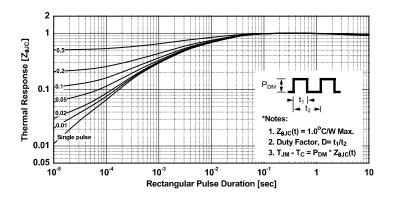
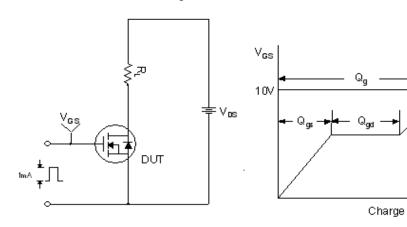


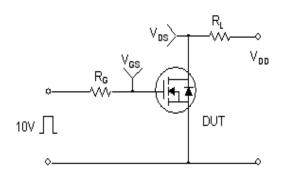
Figure 11. Transient Thermal Response Curve

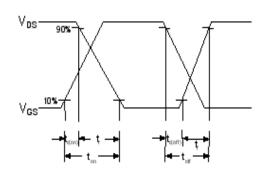


Gate Charge Test Circuit & Waveform

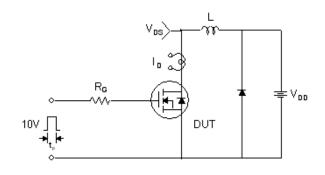


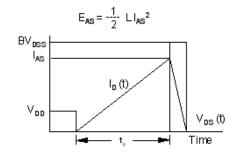
Resistive Switching Test Circuit & Waveforms



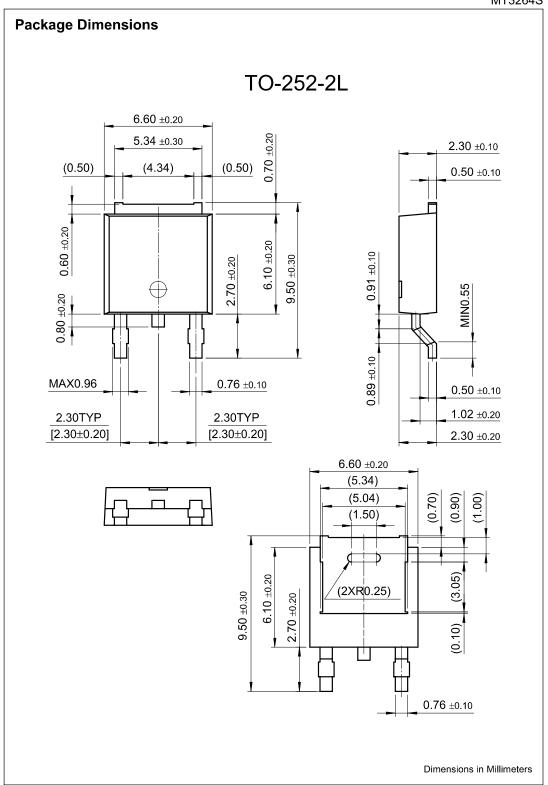


Unclamped Inductive Switching Test Circuit & Waveforms





Peak Diode Recovery dv/dt Test Circuit & Waveforms Driver **≑** V D D **∏** V g s + dv/dt controlled by R $_{6}$ + I $_{8.0}$ controlled by pulse period Gate Pulse Width Gate Pulse Period V _{G S} 1 0 V (Driver) $\boldsymbol{I}_{\text{FM}}$, \boldsymbol{B} ody \boldsymbol{D} iode Forward Current $I_{\,s\,D}$ (DUT) Body Diode Reverse Current $\gamma_{\ D\ S}$ (D U T) Body Diode Recovery dv/dt Body Diode Forward Voltage Drop



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